



N 沟道增强型场效应晶体管

N-CHANNEL MOSFET

FHS100N09A

主要参数 MAIN CHARACTERISTICS

ID	100 A
VDSS	90 V
Rdson-typ (@Vgs=10V)	6.5 mΩ
Qg-typ	60nC

用途 APPLICATIONS

电池管理系统 BMS

产品特性 FEATURES

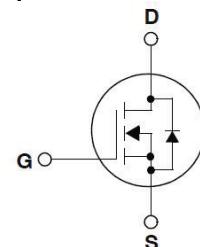
低栅极电荷	Low gate charge
低 Crss (典型值 350pF)	Low Crss (typical 350pF)
开关速度快	Fast switching
100%经过雪崩测试	100% avalanche tested
高抗 dv/dt 能力	Improved dv/dt capability
RoHS 产品	RoHS product

封装形式 Package



TO-263
FHS series

等效电路 Equivalent Circuit



绝对最大额定值 ABSOLUTE RATINGS (Tc=25°C)

项目 Parameter	符号 Symbol	数值 Value	单位 Unit
		FHS100N09A	
最高漏极—源极直流电压 <i>Drain-Source Voltage</i>	VDS	90	V
连续漏极电流* <i>Drain Current -continuous *</i>	Id (Tc=25°C)	100	A
	Id (Tc=100°C)	72	A
最大脉冲漏极电流 (注 1) <i>Drain Current – pulse (note 1)</i>	Idm	400	A
最高栅源电压 <i>Gate-Source Voltage</i>	VGS	±20	V
单脉冲雪崩能量 (注 2) <i>Single Pulsed Avalanche Energy (note 2)</i>	EAS	340	mJ
雪崩电流 (注 1) <i>Avalanche Current (note 1)</i>	IAR	18	A
重复雪崩能量 (注 1) <i>Repetitive Avalanche Current (note 1)</i>	EAR	20	mJ
二极管反向恢复最大电压变化速率 (注 3) <i>Peak Diode Recovery dv/dt (note 3)</i>	dv/dt	5.0	V/ns
耗散功率 <i>Power Dissipation</i>	PD (TC=25°C)	230	W
	-Derate above 25°C	1.53	W/°C
最高结温及存储温度 <i>Operating and Storage Temperature Range</i>	TJ, TSTG	-55~+175	°C
引线最高焊接温度 <i>Maximum Lead Temperature for Soldering Purposes</i>	TL	300	°C

*漏极电流由最高结温限制

*Drain current limited by maximum junction temperature

电特性 ELECTRICAL CHARACTERISTICS

项目 Parameter	符号 Symbol	测试条件 Tests conditions	最小值 Min	典型值 Typ	最大值 Max	单位 Units	
关态特性 Off -Characteristics							
漏一源击穿电压 Drain-Source Voltage	BVDSS	Id=250μA, Vgs=0V	90	-	-	V	
击穿电压温度特性 Breakdown Voltage Temperature Coefficient	ΔBVDSS/Δ TJ	Id=250μA, referenced to 25°C	-	0.085	-	V/°C	
零栅压下漏极漏电流 Zero Gate Voltage Drain Current	Idss	Vds=85V, Vgs=0V, Tc=25°C	-	-	1	μA	
		Vds=68V, Tc=125°C	-	-	10	μA	
栅极体漏电流 Gate-body leakage current	Igss (F/R)	Vds=0V, Vgs =±20V	-	-	±100	nA	
通态特性 On-Characteristics							
阈值电压 Gate Threshold Voltage	VGS(th)	Vds = VGS , Id=250μA	2.0	-	4.0	V	
静态导通电阻 Static Drain-Source On-Resistance	Rds(ON)	Vgs =10V , Id=40A	-	6.5	8	mΩ	
正向跨导 Forward Transconductance	gfs	Vds = 15V, Id=40A (note 4)	-	80	-	S	
动态特性 Dynamic Characteristics							
栅电阻 Gate Resistance	Rg	f=1.0MHz, VDS OPEN	-	1.8	-	Ω	
输入电容 Input capacitance	Ciss	Vds=25V, Vgs =0V, f=1.0MHz	-	3400	-	pF	
输出电容 Output capacitance	Coss		-	1300	-		
反向传输电容 Reverse transfer capacitance	Crss		-	350	-		
开关特性 Switching Characteristics							
延迟时间 Turn-On delay time	td(on)	VDS=40V, Id=30A, RG=25Ω VGS =10V (note 4, 5)	-	17	-	ns	
上升时间 Turn-On rise time	tr		-	24	-	ns	
延迟时间 Turn-Off delay time	td(off)		-	35	-	ns	
下降时间 Turn-Off Fall time	tf		-	14	-	ns	
栅极电荷总量 Total Gate Charge	Qg	VDS =64V , Id=30A , VGS =10V (note 4, 5)	-	60	-	nC	
栅一源电荷 Gate-Source charge	Qgs		-	13	-	nC	
栅一漏电荷 Gate-Drain charge	Qgd		-	16	-	nC	
漏一源二极管特性及最大额定值 Drain-Source Diode Characteristics and Maximum Ratings							
正向最大连续电流 Maximum Continuous Drain -Source Diode Forward Current	Is		-	-	100	A	
正向最大脉冲电流 Maximum Pulsed Drain-Source Diode Forward Current	ISM		-	-	400	A	
正向压降 Drain-Source Diode Forward Voltage	Vsd	Vgs=0V, Is=30A	-	0.9	1.3	V	
反向恢复时间 Reverse recovery time	trr	Vgs=0V, Is=30A ,dI/dt=100A/μs (note 4)	-	65	-	ns	
反向恢复电荷 Reverse recovery charge	Qrr		-	110	-	nC	

热特性 THERMAL CHARACTERISTIC

项目 Parameter	符号 Symbol	最大值 Max	单位 Unit
结到管壳的热阻 Thermal Resistance, Junction to Case	R _{th(j-c)}	0.65	°C/W
结到环境的热阻 Thermal Resistance, Junction to Ambient	R _{th(j-A)}	62.5	°C/W

注释:

- 1: 脉冲宽度由最高结温限制
- 2: L=1mH, I_{AS}=18A, V_{DD}=48V, R_G=25 Ω, 起始结温 T_J=25°C
- 3: I_{SD} ≤ 100A, di/dt ≤ 300A/μs, V_{DD}≤BV_{DSS}, 起始结温 T_J=25°C
- 4: 脉冲测试: 脉冲宽度 ≤300μs, 占空比≤2%
- 5: 基本与工作温度无关

Notes:

- 1: Pulse width limited by maximum junction temperature
- 2: L=1mH, I_{AS}=18A, V_{DD}=48V, R_G=25 Ω, Starting T_J=25°C
- 3: I_{SD} ≤ 100A, di/dt ≤ 300A/μs, V_{DD}≤BV_{DSS}, Starting T_J=25°C
- 4: Pulse Test: Pulse Width ≤300μs, Duty Cycle≤2%
- 5: Essentially independent of operating temperature

典型特性曲线

Typical Characteristics

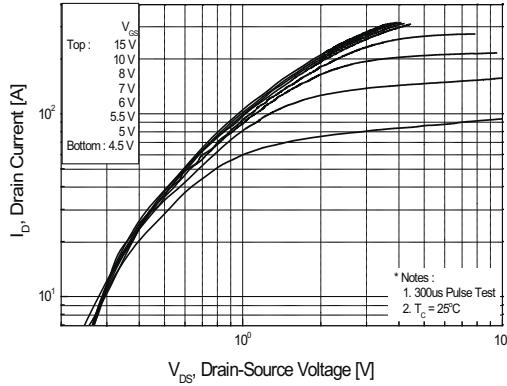


Figure 1. On Region Characteristics

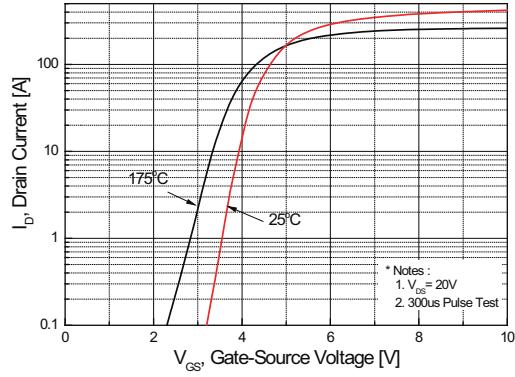


Figure 2. Transfer Characteristics

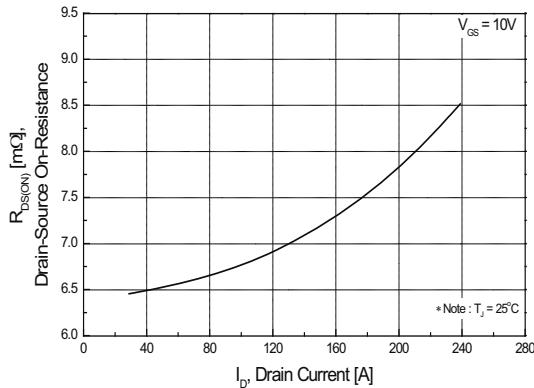


Figure 3. On Resistance Variation vs. Drain Current and Gate Voltage

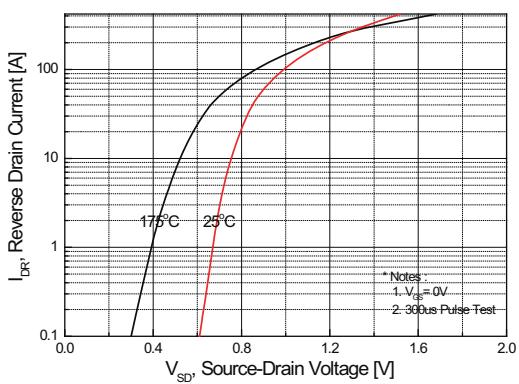


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

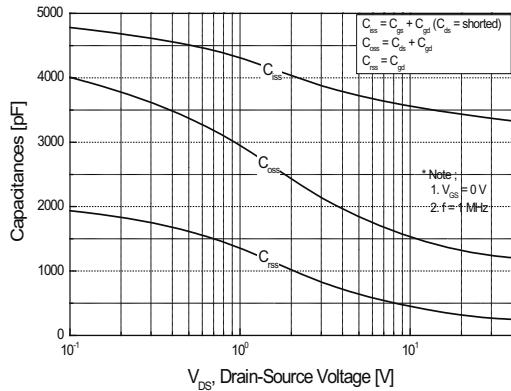


Figure 5. Capacitance Characteristics

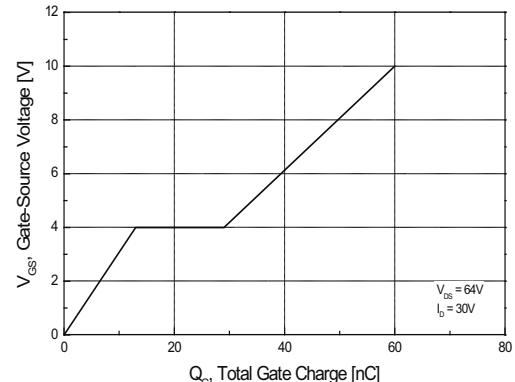


Figure 6. Gate Charge Characteristics

典型特性曲线 (续)

Typical Characteristics (continued)

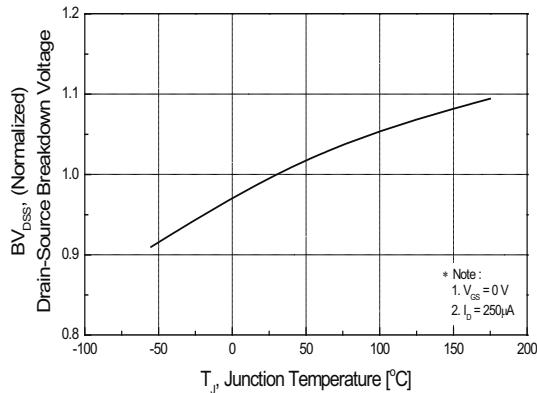


Figure 7. Breakdown Voltage Variation vs Temperature

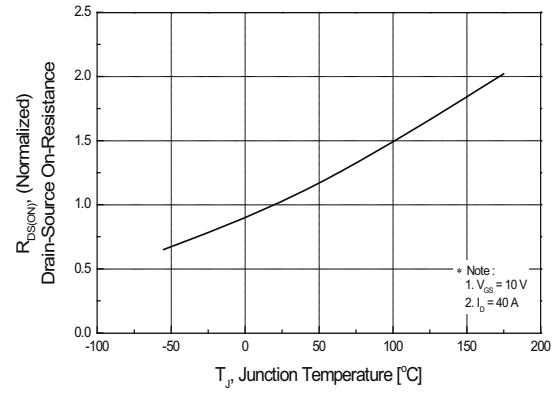


Figure 8. On-Resistance Variation vs Temperature

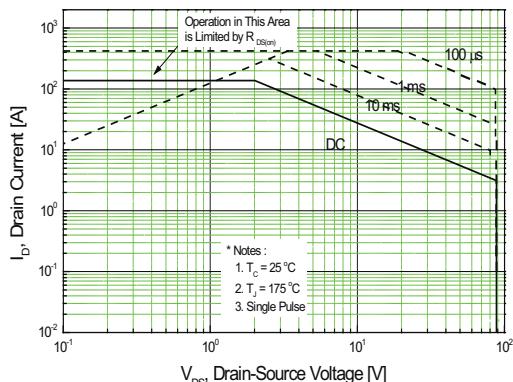


Figure 9. Maximum Safe Operating Area

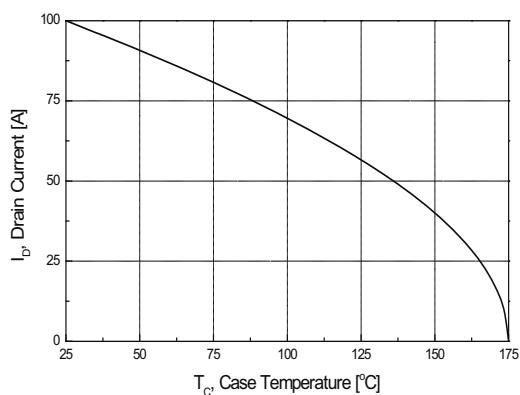


Figure 10. Maximum Drain Current vs Case Temperature

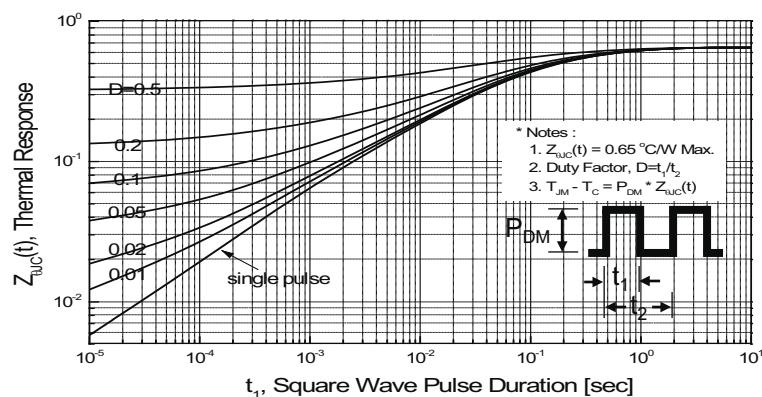


Figure 11. Transient Thermal Response Curve

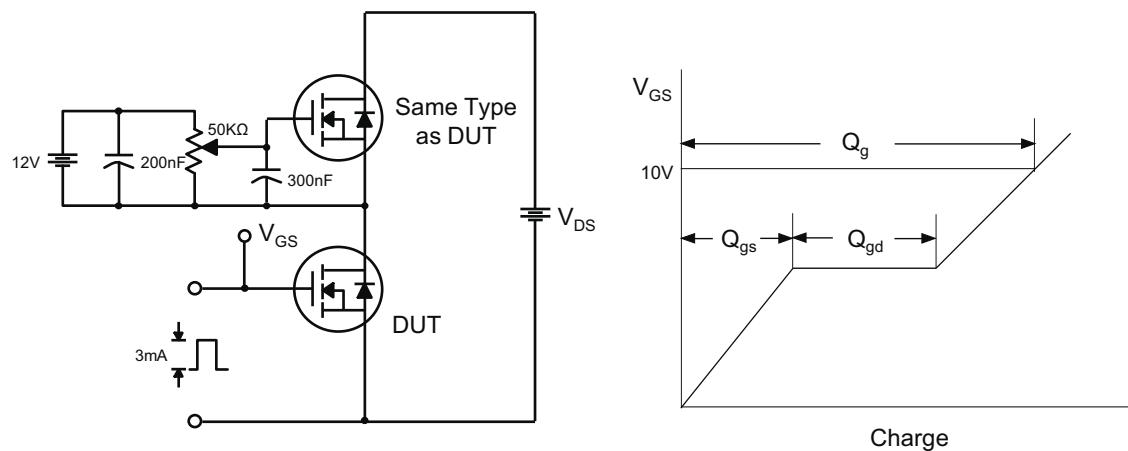


Fig 12. Gate Charge Test Circuit & Waveform

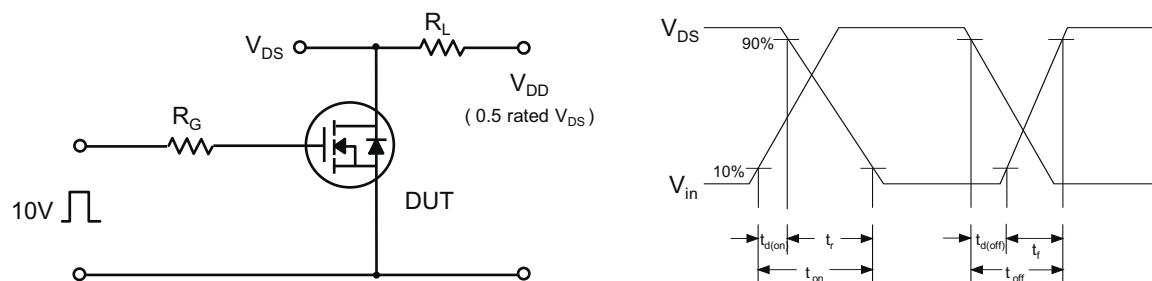


Fig 13. Resistive Switching Test Circuit & Waveforms

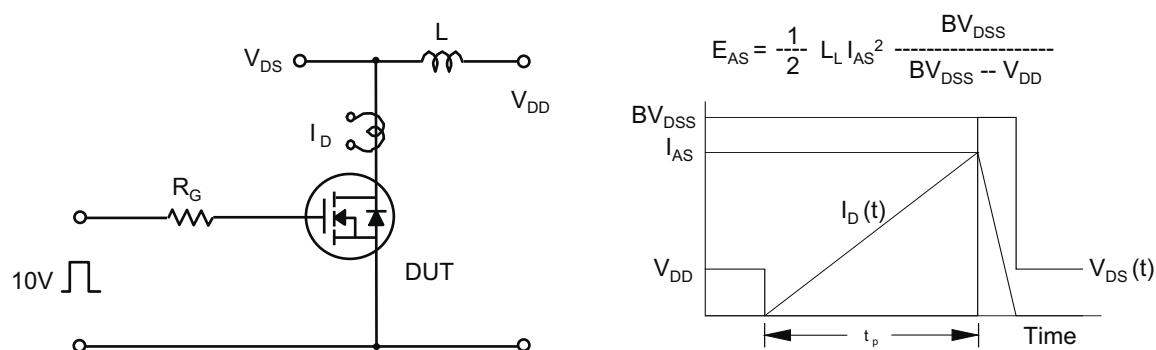


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms

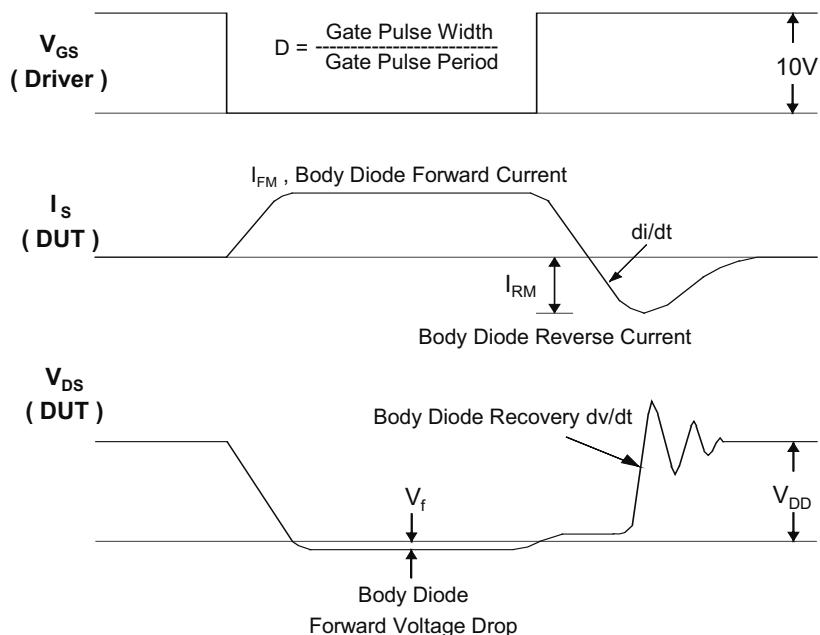
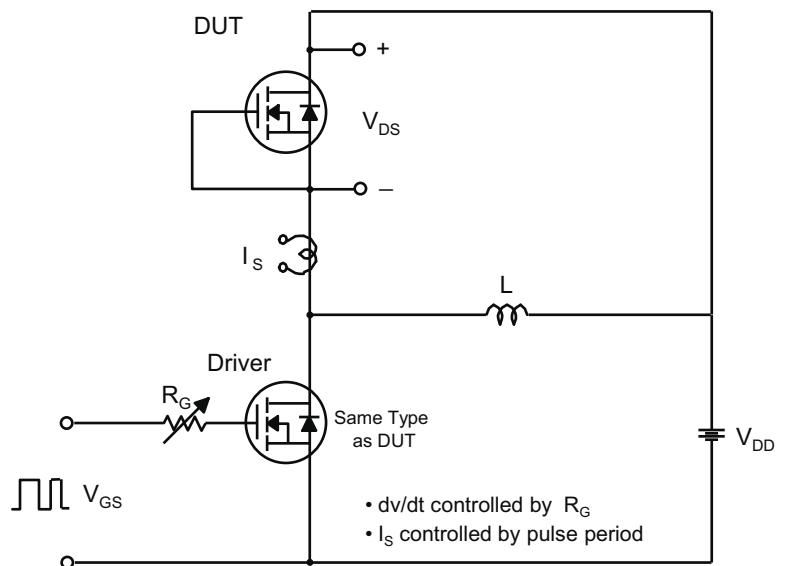
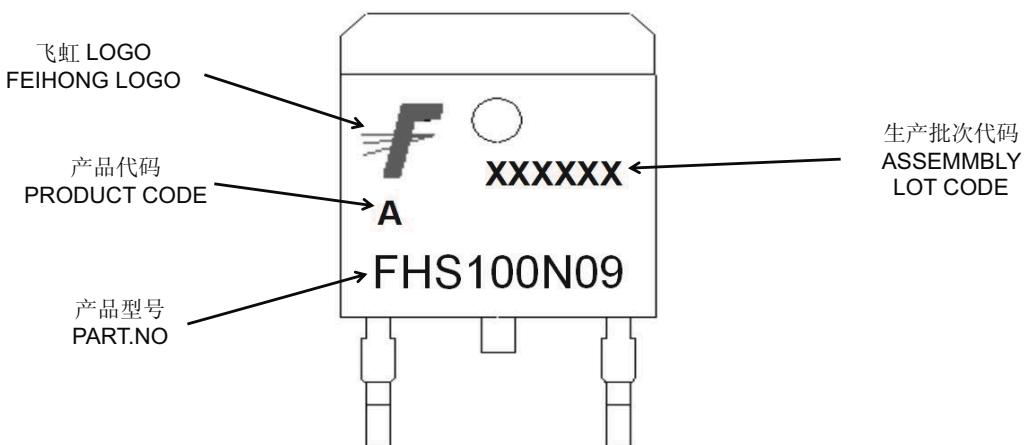


Fig 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

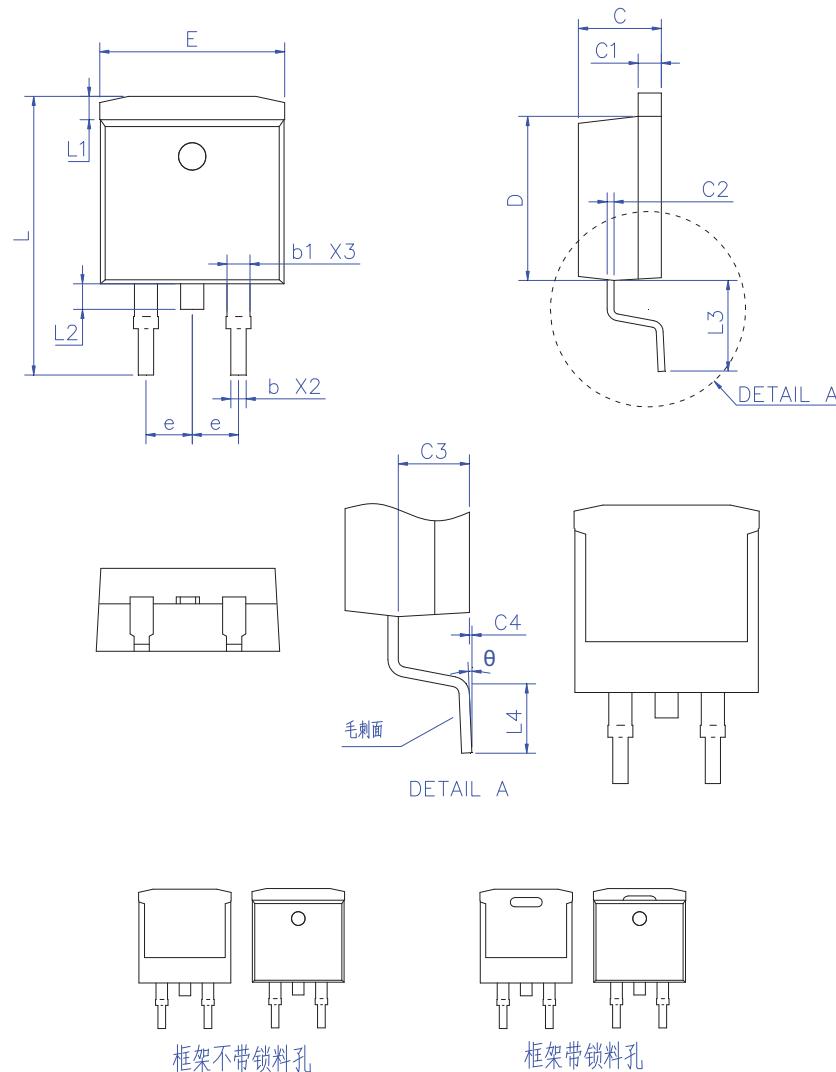
印记 Marking:



外形尺寸:

Package Dimension:

TO-263



DIM	MILLIMETERS	
	MIN	MAX
E	9.80	10.50
L	14.60	15.80
L1	1.00	1.55
L2	1.30	1.70
L3	4.50	5.50
L4	2.10	2.90
b	0.60	0.99
b1	1.00	1.50
C	4.30	4.80
C1	1.10	1.45
C2	0.25	0.52
C3	2.40	2.80
C4	0	0.25
D	8.50	9.50
θ	0°	8°
e	Typical	2.54

(Unit: mm)